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SUPERFUND TECHNICAL ASSESSMENT AND RESPONSE TEAM
EPA CONTRACT 68-W5-0019

N/M
Comments
to STR 1
(2nd set)
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15 July 1996

Mr. Nicholas Magriples
U.S. Environmental Protection Agency
Removal Action Branch
2890 Woodbridge Avenue
Edison, NJ 08837

EPA CONTRACT NO.: 68-W5-0019
TDD NO.: 02-96-04-0003
DCN: START-02-F-00394
SUBJECT: CORNELL-DUBILIER ELECTRONICS -
REVISED SAMPLING TRIP REPORT &
PRELIMINARY ANALYTICAL RESULTS

Dear Mr. Magriples:

Enclosed please find a photocopy of the Revised Sampling Trip Report (STR) for the Cornell-Dubilier Electronics Site; the STR addresses EPA comments provided on 12 July 1996. I am also forwarding all of the preliminary laboratory analytical results that we have received to date. If you should have any questions or comments, do not hesitate to call.

Very Truly Yours,

ROY F. WESTON, INC.

Kathy Campbell
START PM

Enclosures



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SUPERFUND TECHNICAL ASSESSMENT AND RESPONSE TEAM
EPA CONTRACT 68-W5-0019

16 September 1996

Mr. Nick Magriples
U.S. Environmental Protection Agency
Removal Action Branch
2890 Woodbridge Avenue
Edison, NJ 08837

TDD NO: 02-96-04-0003C

DOCUMENT CONTROL NO: NA

SUBJECT: CORNELL-DUBILIER ELECTRONICS

- REVISED SAMPLING TRIP REPORT, 27 & 29 June 1996
- WEEKLY COST REPORT


Dear Mr. Magriples:

Enclosed please find the revised Sampling Trip Report for the 27 & 29 June 1996 soil sampling event at the Cornell-Dubilier Electronics Site located in South Plainfield, Middlesex County, New Jersey. This revision reflects the changes to Tables 1 and 2 that you requested during our telephone conversation on 12 September, as well as the inclusion of the second laboratory in Section 4 and one change in Section 8 ('concrete' replaced 'asphalt' in the description of subsurface conditions at sampling locations CDE-S1 and CDE-S2). In addition, I have included the weekly cost report for the past week.

If you have any questions or comments, do not hesitate to call.

Very truly yours,

ROY F. WESTON, INC.


Christoph Stannik
Project Manager

Enclosures

cc: TDD File

SAMPLING TRIP REPORT

SITE NAME: Cornell-Dubilier Electronics

EPA I.D. NO.: GZ

SAMPLING DATES: 27 & 29 June 1996

1. Site Location: Refer to Figure 1
2. Sample Locations: Refer to Figure 2
3. Sample Descriptions: Refer to Tables 1 and 2
4. Laboratory Receiving Samples:

<u>Sample Type</u>	<u>Name and Address of Laboratory</u>
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Soil/Aqueous - TCL PCBs and Total Metals for Ag, Cr, Cd, Hg, and Pb	ICM Laboratory 1052 Route 10 Randolph, NJ 07869
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Sediment - Total Organic Carbon (TOC)	ICM Laboratory 1052 Route 10 Randolph, NJ 07869
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Grain Size Distribution	Tectonic Engineering Consultants P.C. P.O. Box 447, 600 Route 32 Highland Mills, NY 10930
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5. Sample Dispatch Data:

The following samples were hand-delivered by Region II START personnel to ICM Laboratory on 28 June 1996 at approximately 1050 hours: 26 soil samples and one aqueous sample for TCL PCB and Total Metals (Ag, Cr, Cd, Hg, and Pb) analyses, and one sediment sample for TOC and grain size distribution analyses.

The following samples were hand-delivered by Region II START personnel to ICM Laboratory on 1 July 1996 at approximately 1000 hours: 22 soil samples and one aqueous sample for TCL PCB and Total Metals (Ag, Cr, Cd, Hg, and Pb) analyses.

6. On-Site Personnel:

<u>Name</u>	<u>Company</u>	<u>Duties on Site</u>
Nick Magriples	Region II EPA	On-Scene Coordinator
Christoph Stannik	Region II START	Task Manager/Documentation/Sampler
Jennifer Leahy*	Region II START	QC Coordinator/Documentation
Kevin McGarry	Region II START	Sampler
Swamy Ketha	Region II START	Sampler/Equipment Decontamination
Diane Delap	Region II START	Sampler/Equipment Decontamination
Patrick Austin	Region II START	Sampler/Equipment Decontamination

* START Leahy was not on site for second sampling date (29 June 1996).

7. Weather Conditions:

27 June - clear skies/sun, temperatures in 80F° range, winds estimated to be 10 to 15 mph.

29 June - sunny, approximately 78°F, winds 0 to 5 mph E to SE.

8. Additional Comments:

A total of 48 soil samples, including four field duplicate samples, were collected for TCL PCBs, and Total Metals for Ag, Cr, Cd, Hg, and Pb analyses. One sediment sample was collected for TOC and grain size distribution analyses. In addition, two rinsate blanks and four matrix spike/matrix spike duplicate (MS/MSD) samples were collected and delivered to the laboratory to meet QA/QC requirements for a QA-2 data quality objective level.

START collected Subsurface Soil Sample Nos. CDE-SS1 and CDE-SS2 at a depth of 3 to 6 inches below ground surface. The proposed sample depth range of 3 to 12 inches could not be achieved due to the presence of a concrete layer at 6 inches below ground surface. Due to the dark appearance of the subsurface soils at Sample Location No. CDE-SS12, a Chlor-n-Soil PCB screening test (detection limit - 50 ppm) was performed on soil obtained from the auger boring. The results of the screening test indicated the presence of PCBs at approximately 50 ppm. The soil samples collected on Saturday, 29 June 1996, were monitored by START for storage cooler temperature until delivery to the laboratory on Monday, 1 July 1996. The rinsate blanks were prepared using demonstrated analyte-free deionized water. Upon direction of the OSC, four proposed storm drain sediment samples were not collected.

The analytical request submitted for the current phase of sampling includes both the samples collected on 27 and 29 June 1996 and the test pit excavation samples scheduled to be collected on 16 July 1996. A separate Sampling Trip Report will follow to address the test pit sampling event.

9. Report ^{REVISED} Prepared by: Christoph Stannik Date: 9/16/96
10. Report Reviewed by: [Signature] Date: 9/16/96
11. Report Approved by: _____ Date: _____

Table 1: Sample Descriptions
Cornell-Dubilier Electronics
South Plainfield, NJ
Sampling Date: 27 June 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [inches]	Location
CDE-S1 ^a	0950	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	125 ft. southeast of west corner post of driving school fence, then 40 ft. southwest.
CDE-SS1 ^a	1000	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-6 ^b	Same location as Sample No. CDE-S1.
CDE-S2	1010	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	280 ft. southeast of west corner post of driving school fence, then 25 ft. southwest.
CDE-SS2	1020	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-6 ^b	Same location as Sample No. CDE-S2.
CDE-S3	1030	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	30 ft. southwest of south corner post of driving school fence, then 94 ft. southeast.
CDE-SS3	1040	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S3.
CDE-S4	1045	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	103 ft. northeast of south corner post of driving school fence, then 23 ft. southeast.
CDE-SS4	1055	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S4.
CDE-S5	1335	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	7 ft. southeast of east corner post of driving school fence.
CDE-SS5	1340	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S5.

^a MS/MSD sample - indicates additional sample volume was submitted to the laboratory for Matrix Spike/Matrix Duplicate (MS/MSD) analysis.

^b Concrete layer at 6 inches below ground surface.

Table 1: Sample Descriptions
Cornell-Dubilier Electronics
South Plainfield, NJ
Sampling Date: 27 June 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [inches]	Location
CDE-S6	1350	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	87 ft. northeast of east corner post of driving school fence, then 28 ft. southeast.
CDE-SS6	1400	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S6.
CDE-S7	1415	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	35 ft. northeast from east corner post of driving school fence, then 137 ft. southeast.
CDE-SS7	1425	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S7.
CDE-S8	1525	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	138 ft. northeast from east corner post of driving school fence, then 25 ft. southeast; 3 ft. from inactive rail line in middle of footpath and 8 ft., 7 inches from old gate post at the RR overpass.
CDE-SS8	1530	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S8.
CDE-S9	1535	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	139 ft. northeast from east corner post of driving school fence, then 154 ft. northwest.
CDE-SS9	1540	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S9.
CDE-S10	1545	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	202 ft. northwest, along fence line, from east corner post of driving school fence, then 193 ft. northeast.
CDE-SS10	1550	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample NO. CDE-S10.

Table 1: Sample Descriptions
Cornell-Dubilier Electronics
South Plainfield, NJ
Sampling Date: 27 June 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [inches]	Location
CDE-S11	1600	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	234.6 ft. northwest, along fence line, from east corner post of driving school fence, then 91.4 ft. northeast.
CDE-SS11	1610	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-S11.
CDE-S12	1700	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	83 ft. northwest and 50 ft., 6 inches east from east corner of Building No. 11 in the gravel driveway.
CDE-SS12	1710	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-15	Same location as Sample No. CDE-S12.
CDE-S26 ^c	1350	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	Same location as Sample No. CDE-S6.
CDE-SS26 ^c	1400	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-12	Same location as Sample No. CDE-SS6.
CDE-RIN1	1145	Aqueous	Composite	TCL PCBs, Ag, Cr, Cd, Hg, Pb	N/A	Composite trowel, bowl, and auger rinsate collected in the field.
CDE-SED4	1520	Sediment	Grab	TOC; grain size distribution	0-2	7 ft. from south side of drainage pipe which carries creek water flow under the abandoned railroad overpass.

^c Duplicate sample - indicates that the sample was collected as an environmental field duplicate.

Table 2: Sample Descriptions
Cornell-Dubilier Electronics
South Plainfield, NJ
Sampling Date: 29 June 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [inches]	Location
CDE-S13	0835	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	66 ft. northeast from the northeast corner of Building No. 11, then 50 ft. to southeast; on driveway south of water tank.
CDE-SS13	0915	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-11	Similar location as Sample No. CDE-S13, except 2 ft. closer to water tank at edge of driveway.
CDE-S14	0835	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-2	35 ft. southwest of southwest corner of Building No. 14, then 46 ft. east; northeast of water tank.
CDE-SS14	0855	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-15	Same location as Sample Location No. CDE-S14.
CDE-S15*	0935	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	21 ft., 4 in. northeast from north corner post of truck driving school (measured along wooden fence that extends northeast of post), then 13 ft., 6 in. northwest onto gravel driveway.
CDE-SS15*	1000	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-15	Same location as Sample No. CDE-S15.
CDE-S16	0855	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	19 ft. southeast of southwest corner of Building No. 9B, then 14 ft., 6 in. southwest onto gravel driveway.
CDE-SS16	0915	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	6-15	Same location as Sample No. CDE-S16.
CDE-S17	1400	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	52 ft. southeast of southwest corner of Building No. 14 (parallel to west side of building), then 6 ft. northeast.
CDE-SS17	1420	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	4-16	Same location as Sample No. CDE-S17.

MS/MSD sample - indicates additional sample volume was submitted to the laboratory for matrix spike/matrix spike duplicate (MS/MSD) analysis.

Table 2: Sample Descriptions
Cornell-Dubilier Electronics
South Plainfield, NJ
Sampling Date: 29 June 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [inches]	Location
CDE-S18	1355	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	81 ft. southeast of the southwest corner of Building No. 13 (parallel to southwest side of building), then 10 ft. southwest.
CDE-SS18	1415	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-13	Same location as Sample No. CDE-S18.
CDE-S19	1145	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	66 ft. northwest of Utility Pole No. PS6726SPE and 49 ft from southeast corner of concrete loading dock at northwest end of Building No. 12.
CDE-SS19	1210	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	3-13	Same location as Sample No. CDE-S19.
CDE-S20	1445	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	19 ft. northeast of northeast corner of Building No. 13 onto gravel driveway, then 41 feet northwest.
CDE-SS20	1500	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	4-16	Same location as Sample No. CDE-S20.
CDE-S21	1035	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	68 ft. northeast of west corner post of driving school fence, then 25 ft. north onto gravel driveway.
CDE-SS21	1100	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	6-14	Same location as CDE-S21.
CDE-S22	1045	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	39 ft. southwest of the southeast corner of Building No. 12; gravel driveway.
CDE-SS22	1140	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	14-18	Same location as Sample No. CDE-S22; collected within the gravel layer.

Table 2: Sample Descriptions
Cornell-Dubilier Electronics
South Plainfield, NJ
Sampling Date: 29 June 1996

Sample Number	Time	Matrix	Sample Type	Analysis	Sample Depth [inches]	Location
CDE-S28 ^b	1400	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	0-3	Same location as Sample No. CDE-S17.
CDE-SS28 ^b	1420	Soil	Grab	TCL PCBs, Ag, Cr, Cd, Hg, Pb	4-16	Same location as Sample No. CDE-SS17.
CDE-RIN 2	1235	Aqueous	Composite	TCL PCBs, Ag, Cr, Cd, Hg, Pb	N/A	Composite trowel, bowl, and auger rinsate collected in the field.

^b Duplicate sample - indicates that the sample was collected as an environmental field duplicate.